PCN Number:			2014	20140829000 PC									CN Date: 9/02/2014			
					ternative Wire Base Metal for Selected VQFN Device(s)											
Customer Contact: PC			PCN M	anager		Phone:	+1(214)480-6037			De	ept:	Quality Services				
Proposed 1 <sup>st</sup> Ship Date:			2/02/	'201 <sub>4</sub>	4	<b>Estimated Sample Availabilit</b>					Date provided at sample request					
Change Type:																
	Assembly Site					D	esign					afer Bump Site				
$\boxtimes$	Assembly Process					Di	ata Shee					afer Bump Material				
	Assembly Materials				Part numbe				change				fer Bump Process			
	Mechanical Specification											afer Fab Site				
	Packing/Shipping/Labeling			ng		Te	est Proce					Vafer Fab Materials				
											Wafe	Wafer Fab Process				
PCN Details																
Des	Description of Change:															
Texas Instruments is pleased to announce the qualification of Au as an additional bond wire option for devices listed in "Product affected" section below. Devices will remain in current assembly facility and there will be no other piece part changes.																
Reason for Change:																
Manufacturing flexibility.																
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):																
None.																
Cha	Changes to product identification resulting from this PCN:															
Non	None.															
Pro	Product Affected:															
SN	SN65LVDS822RGZR SN65LVDS822RGZT															
Qualification Data - Approved August, 2014																
			eloped for the validation of this change. The													
vali	validates that the proposed change meets the applicable released technical specifications.															
Qual Vehicle 1: SN65LVDS822RGZ (MSL 3-260C)																
Package Construction Details																
,			TI-C			Mold Compou				4208625						
			48-R		FN	Mount Compound				4207768						
<u> </u>				NiPd				Bond Wire:				0.96 Mil Dia., Au				
Qualification:   Plan					est R	les	ults									
Reliability Test					Conditions								Sample Size/Fail			
Electrical Characterization					Per Datasheet Parameters								Pass			
Ball Bond Shear					76 balls, 3 units min							Pass				
Bond Pad Cratering Check					Per Manufacturing Specifications							Pass				
Bond Pull					76 Wire, 3 units min							Pass				

## Reference Qualification Data - Approved September, 2009 This qualification has been developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications. Qual Vehicle 1: SN65LVCP40RGZ (MSL 3-260C) Package Construction Details Assembly Site: TI-Clark Mold Compound: 4208625 48-RGZ, VQFN # Pins-Designator, Family: Mount Compound: 4207768 Lead frame (Finish, Base): NiPdAu, Cu Bond Wire: 0.96 Mil Dia., Au Qualification: Plan ☐ Test Results Reliability Test Conditions Sample Size/Fail 77/0 \*\*Autoclave 121C (96 Hrs) 82/0 \*\*Temperature Cycle -65/150C (500 cycles) 77/0 \*\*High Temp Storage Bake 170C (420 Hrs) 116/0 \*\*Life Test 155C (240 Hrs) \*\*Biased HAST 130C/85%RH (96 Hrs) 77/0 Pass Manufacturability (Assembly) (per mfg. Site specification) 12/0 Level 3-260C Moisture Sensitivity Notes \*\*- Preconditioning sequence: Level 3-260C. Qual Vehicle 2: SH6966ACCORGCRG4 (MSL 3-260C) Package Construction Details Assembly Site: TI-Clark Mold Compound: 4208625 # Pins-Designator, Family: 64-RGC, VQFN Mount Compound: 4207768 Lead frame (Finish, Base): NiPdAu, Cu Bond Wire: 1.15 Mil Dia., Au Qualification: Plan **⊠** Test Results Reliability Test Conditions Sample Size/Fail 77/0 \*\*Autoclave 121C (96 Hrs) 77/0 \*\*Thermal Shock -65/150C (500 cycles) 82/0 \*\*Temperature Cycle -65/150C (500 cycles) 77/0 \*\*High Temp Storage Bake 170C (420 Hrs) 141/0 \*\*Life Test 125C (1000 Hrs) \*\*Biased HAST 130C/85%RH (96 Hrs) 77/0 22/0 Solderability 8 Hours Steam Age 22/0 Salt Atmosphere 24 Hrs 5/0 (top side only) X-ray Manufacturability (Assembly) Pass (per mfg. Site specification) Moisture Sensitivity Level 3-260C 12/0

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

\*\*- Preconditioning sequence: Level 3-260C.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com